EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	2	"7058869".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/31 23:18
L5	2	"4503386".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/31 23:31
S1	2899	(pattern adj (generator generation)) and (memory with (test tester testing tested))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/04 17:01
S2	18	(pattern adj (generator generation)) and (memory with (test tester testing tested)) and ((row and column) with size)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 10:46
S3	48	("6178534" "5329167" "5978944" "5640402" "6453436" "5557619" "5442641" "5386392" "5341096" "6191603" "5193092" "5513186" "4989209" "5430735" "5550841" "5657329" "5677917" "5881067" "5886901" "5925144" "6157583" "6212119" "6212119" "5717700" "5477545" "5642362" "5719878" "4996691" "5633606" "5651013" "5774003" "4377757" "5640404" "6014763" "6108805" "6223313" "6223313" "4947357" "5032783" "5221865" "5225724" "5280616" "5381418" "5534798" "5610927" "5636228" "5652527" "5671234" "5691991" "5729553").pn.	USPAT	OR	ON	2006/08/31 23:18
S4	4887	(testing tested test) with ((scan shift) near2 (path chain element latch))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 11:06
S5	1496	((testing tested test) with ((scan shift) near2 (path chain element latch))).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 10:52

S6	976	((testing tested test) with ((scan shift) near2 (path chain element latch))). clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 10:52
S7	350	S5 and S6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 10:53
S8	253827	(path or chain).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/28 13:25
S9	74	S8 and S7	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 10:58
S10	0	U5-6,941,498 U5-6,701,476	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 10:58
S11	4	"6941498".pn. "6701476".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 10:59
S12	13	((testing tested test) with ((scan shift) near2 (path chain element latch))) and (defective adj latch)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/30 22:14
S13	47	((testing tested test) with ((scan shift) near2 (path chain element latch))) and (fail$4 adj latch)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 11:15
S14	17	((testing tested test) with ((scan shift) near2 (path chain element latch))) same (fail$4 adj latch)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/15 11:15
S15	6953	(scan near2 (path chain element register latch flip-flop flop)) same (test testing tested tester verify verification verified verifying diagnose diagnosis diagnosed diagnosing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/25 19:33

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S16	650	(((scan near2 (path chain element register latch flip-flop flop)) same (test testing tested tester verify verification verified verifying diagnose diagnosis diagnosed diagnosing))) and ((flush flushing flushed) (all adj (zero one)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/25 19:35
S17	357	((((scan near2 (path chain element register latch flip-flop flop)) same (test testing tested tester verify verification verified verifying diagnose diagnosis diagnosed diagnosing))) and ((flush flushing flushed) (all adj (zero one)))) and ((record store save recorded recording stored saved saving storing) near3 result)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/25 19:37
S18	273	((((scan near2 (path chain element register latch flip-flop flop)) same (test testing tested tester verify verification verified verifying diagnose diagnosis diagnosed diagnosing))) and ((flush flushing flushed) (all adj (zero one)))) and (((record store save recorded recording stored saved saving storing) and (analyze analysis analyzed analysed analyzing review reviewing reviewed evaluate evaluation evaluated evaluating)) near3 (output result))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/25 19:41
S19	0	(((((scan near2 (path chain element register latch flip-flop flop)) same (test testing tested tester verify verification verified verifying diagnose diagnosis diagnosed diagnosing))) and ((flush flushing flushed) (all adj (zero one)))) and (((record store save recorded recording stored saved saving storing) and (analyze analysis analyzed analysed analyzing review reviewing reviewed evaluate evaluation evaluated evaluating)) near3 (output result))	JPO	OR	ON	2006/08/25 19:41

S20	118	(((((scan near2 (path chain element register latch flip-flop flop)) same (test testing tested tester verify verification verified verifying diagnose diagnosis diagnosed diagnosing))) and ((flush flushing flushed) (all adj (zero one)))) and (((record store save recorded recording stored saved saving storing) and (analyze analysis analyzed analysed analyzing review reviewing reviewed evaluate evaluation evaluated evaluating)) near3 (output result))	USPAT	OR	ON	2006/08/25 19:56
S21	49	("5347523" "6158033" "4604746" "5717695" "6044025" "6490702" "6711708" "5796751" "5640402" "4630270" "6453436" "6212656" "6212656" "5999014" "5574733" "5928374" "5260947" "5341096" "5502731" "5522063" "5544173" "5867507" "5909452" "6021513" "6032278" "6185721" "5008618" "5333139" "5430735" "5519715" "5657329" "5748646" "5774475" "5872795" "5917832" "5978945" "5983378" "6014763" "6073261" "6243843" "4989209" "5014065" "5279636" "5323400" "5406216" "5509019" "5592493" "5610926" "5715171" "5726997").pn.	USPAT	OR	ON	2006/08/25 19:56
S22	7	S21 and ((flush flushing flushed) (all adj (zero one)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 17:34
S23	8150	look adj ahead	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 17:34
S24	3437	((look adj ahead) (look-ahead)) and (scan shift)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 17:35
S25	68924	((look adj ahead) (look-ahead)) and (scan shift) and ABIST LBIST disturb	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 17:35

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S26	1	((look adj ahead) (look-ahead)) and (scan shift) and ABIST and LBIST and deterministic and voltage and disturb	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 17:38
S27	3	((look adj ahead) (look-ahead)) and (scan shift) and deterministic and voltage and disturb	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 17:38
S28	3	((look adj ahead) (look-ahead)) and (scan shift) and deterministic and disturb	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 17:38
S29	60	((look adj ahead) (look-ahead)) and (scan shift) and disturb	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 22:28
S30	2	"6694454".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 22:30
S31	2	"7058869".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/27 22:30
S32	362	(path or chain).ti. and ((fault fail error failed failing failure erroneous faulty) near2 (latch flop flip-flop register element))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/28 13:27
S33	25	(path or chain).ti. and ((fault fail error failed failing failure erroneous faulty) near2 (latch flop flip-flop register element)).ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/28 14:52
S36	2	"6944692".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/30 11:37
S37	13	((testing tested test) with ((scan shift) near3 (path chain element latch))) and (defective adj latch)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/30 22:15

S38	303	((testing tested test) with ((scan shift) near3 (path chain element latch))) and ((defective fail failing bad error erroneous failed) near2 (element flop latch))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/31 09:09
S39	28	((testing tested test) with ((scan shift) near3 (path chain element latch))) and ((defective fail failing bad error erroneous failed) near2 (element flop latch)).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/30 22:37
S40	585	(parallel$4 lateral$4) with (scan adj (chain path element latch flip-flop flop register)) with (pattern test signal)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/30 22:50
S41	96	((parallel$4 lateral$4) with (scan adj (chain path element latch flip-flop flop register)) with (pattern test signal)).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/30 22:49
S42	111	((parallel$4 lateral$4) with (scan adj (chain path element latch flip-flop flop register)) with (pattern test signal)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/30 22:50
S43	12	((parallel$4 lateral$4) with (scan adj (chain path element latch flip-flop flop register)) with (pattern test signal)) and ABIST	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/30 22:50
S44	14	(((testing tested test) with ((scan shift) near3 (path chain element latch))) and ((defective fail failing bad error erroneous failed) near2 (element flop latch))) and abist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/31 23:31
S45	2	"20020035708"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/31 17:02